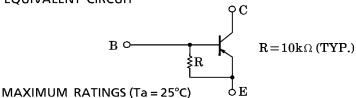
TOSHIBA TRANSISTOR SILICON PNP EPITAXIAL TYPE (PCT PROCESS)

RN6003

MOTOR DRIVE CIRCUIT APPLICATIONS. POWER AMPLIFIER APPLICATIONS. POWER SWITCHING APPLICATIONS.

- With Built-in Bias Resistors
- Simplify Circuit Design
- Reduce a Quantity of Parts and Manufacturing Process
- Small Flat Package
- P_C=1~2W (Mounted on Ceramic substrate)
- Complementary to RN5003

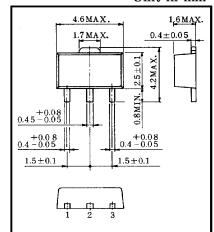
EQUIVALENT CIRCUIT



CHARACTERISTIC	SYMBOL	RATING	UNIT
Collector-Base Voltage	v_{CBO}	-30	V
Collector-Emitter Voltage	v_{CES}	-30	V
Emitter-Base Voltage	$ m V_{EBO}$	-5	V
Collector Current	$\mathbf{I}_{\mathbf{C}}$	-2	Α
Base Current	${f I_B}$	-0.4	Α
Collector Power Dissipation	$P_{\mathbf{C}}$	500	mW
Collector Power Dissipation	$^{\mathrm{P}\mathrm{C}}{}^{*}$	1000	mW
Junction Temperature	$\mathbf{T}_{\mathbf{j}}$	150	°C
Storage Temperature Range	${f T}_{ m stg}$	-55~150	$^{\circ}\mathrm{C}$

^{* :} Mounted on ceramic substrate (250mm $^2 \times 0.8t$)

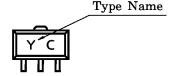
Unit in mm



- BASE
- COLLECTOR (HEAT SINK)
- 3. EMITTER

PW-MINI		
JEDEC	_	
EIAJ	SC-62	
TOSHIBA	2-5K1A	

Weight: 0.05g **MARKING**



ELECTRICAL CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	TINIT
CHARACTERISTIC	SIMBOL	TEST CONDITION	IVIIII .	III.	MAA.	OMII
Collector Cut-off Current	ICBO	$V_{CB} = -30V, I_{E} = 0$	_	_	-0.1	μ A
Emitter Cut-off Current	I_{EBO}	$V_{EB} = -5V, I_C = 0$	-0.385	-0.50	-0.714	mA
Collector-Emitter Breakdown Voltage	V _{(BR)CES}	$I_C = -10 \text{mA}$	-30	_	_	V
DC Current Gain	$h_{FE(1)}$	$V_{CE} = -2V, I_{C} = -0.5A$	100	_	400	
	$h_{FE(2)}$	$V_{CE} = -2V, I_{C} = -2.0A$	30	_		
Collector-Emitter Saturation Voltage	V _{CE(sat)}	$I_C = -1A, I_B = -0.05A$		_	-0.5	V
Base-Emitter Saturation Voltage	V _{BE(sat)}	$I_C = -1A, I_B = -0.05A$			-1.2	V
Transition Frequency	$ m f_{T}$	$V_{CE} = -2V, I_{C} = -0.5A$		120		MHz
Collector Output Capacitance	C_{ob}	$V_{CB} = -10V, I_{E} = 0, f = 1MHz$		40		рF
Resistor	R		7	10	13	$\mathbf{k}\Omega$

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